# C ircularly polarized light em ission in scanning tunneling m icroscopy of m agnetic system s

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Light is produced when a scanning tunneling m icroscope is used to probe a m etal surface. R ecent experiments on cobalt utilizing a tungsten tip found that the light is circularly polarized; the sense of circular polarization depends on the direction of the sam ple m agnetization, and the degree of polarization is of order 10 %. This raises the possibility of constructing a m agnetic m icroscope with very good spatial resolution. W e present a theory of this e ect for iron and cobalt and nd a degree of polarization of order 0.1 %. This is in disagreement with the experiments on cobalt as well as previous theoretical work which found order of m agnitude agreement with the experimental results. However, a recent experiment on iron showed 0.0 2 %. W e predict that the use of a silver tip would increase the degree of circular polarization for a range of photon energies.

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I. IN TRODUCTION

The last ten years have seen a rapid development of the eld of magnetic dichroism, especially where the response of a system to left and right circularly polarized light is probed; so called circular dichroism <sup>1</sup> For a magnetic material this is magnetic circular dichroism (M CD). Experiments involve x-ray absorption,<sup>2</sup> as well as standard photo-em ission techniques.<sup>3</sup>

The possibility of a new method of microscopic measurements of surface magnetism has been suggested by a recent experim ent.<sup>4</sup> In this experim ent, circularly polarized light em itted from a scanning tunneling m icroscope (STM) was observed when the surface of a ferrom agnetic material (Co) was probed with a W tip in a longitudinal con guration (see Fig. 1, the applied magnetic eld is parallel to both the surface plane and to the plane of light detection). The handedness of the circular polarization was found to depend on the direction of the applied eld and the degree of polarization was between 5 and 10%. The results of V azques de Parga and A lvarado<sup>4</sup> looks, at rst sight, to have been corroborated by the theoretical work of Majlis et al.<sup>5</sup> In principle such an effect, if con med, should make it possible to map the m agnetic m icrostructure of a surface by measuring the circular polarization of the emitted light while scanning the surface because a STM tip provides very good spatial resolution.<sup>6</sup> However, a more recent experiment of this type, by Pierce et al.<sup>7</sup> carried out on Fe with a W tip, found 0.0 2% circular polarization.

In this paper we calculate the degree of circular polarization for Fe and Co. We nd two contributions to the circular polarization. The rst is due to the K err rotation of the light em itted in the tunneling process. The second contribution is due to the polarization of the scanning tip by the electric eld of the em itted light. The polarized tip radiates and the radiation undergoes a K err rotation. This second contribution depends on the polarizability of the tip as well as the dielectric properties of the sam ple and can be signi cantly larger than the rst contribution.

We obtain results which are between one and two orders of magnitude smaller than that measured by Vazques de Parga and A lvarado<sup>4</sup> but consistent with the measurements of Pierce et al.<sup>7</sup>. Both workers used W tips, but we nd that for a Ag tip, Co and Fe produce a larger degree of circular polarization for a range of photon energies.

There are other sources of circular polarization that are not m agnetic in origin. For example, experiments by V azques de Parga and A lvarado<sup>8</sup> and theory by Anisim ovas and Johansson<sup>9</sup> show that an asymmetric STM tip can produce a degree of circular polarization on the order of 10 %.

In section II we develop a theory for the degree of circular polarization produced by an STM tip in the presence of a magnetic sample based on the magneto-optic K err e ect. In order to understand the physics of the magnetic circular dichroism in these experiments the tip is modeled by a dipole. The purpose of the dipole model is solely to help to understand the physics and is introduced mainly for pedagogical reasons. In section III the theoretical description of the tip is in proved for the purpose of obtaining reliable numerical estimates of the degree of circular polarization. These results are discussed in section IV.

## II.THEORY

In this section we obtain an expression for the circular polarization of light em itted when an STM tip scans a m agnetic material. The calculation is divided into ve parts: (A) We rst describe the experiment and express the results in terms of Stokes parameters. (B) The electrom agnetic elds in the tip region are related to the elds at the detector. (C) A model for the tip is introduced which makes the problem tractable. (D) The local eld outside the tip is related to the tip polarization, in the presence of a magnetic substrate. (E) The di erent contributions are assembled and we obtain a theoretical expression for the changes in the circular polarization due to a change in the direction of the applied magnetic eld.

#### A. Theoretical expression for M C D

In this section we relate the MCD to the eld am plitudes at the detector. The experim ents by Vazques de Parga and Alvarado<sup>4</sup> and Pierce et al.<sup>7</sup> used the longitudinal con guration, i.e. the applied magnetic eld is parallel to the plane of incidence and in the surface plane of Co(0001) [thin lm grown on Au(111)] and Fe(001) (whisker), respectively. Light was detected at an angle of 30° m easured from the surface and tungsten tips were used in both experiments. The emitted radiation show ed circular polarization which changed when the applied magnetic eld was reversed. W hereas Vazques de Parga and Alvarado<sup>4</sup> used a xed quarter wave plate and carry out the analysis by a linear polarizer, Pierce et al,<sup>7</sup> use a rotating quarter wave plate and a xed linear analyzer. In both experim ents controlm easurem ents were performed on clean Au (111) samples and yielded no change of the polarization of the emitted light upon reversal of the external magnetic eld. The background due to geom etric details of tip-sam ple junctions such as those discussed in Refs. 8 and 9 and any residual dichroism of the view port of the UHV system were removed by reversing the magnetization of the sam ple.

The results of the two groups were very di erent. Pierce et al.<sup>7</sup> found no magnetization dependent circular polarization within an experimental uncertainty of

2 % whereas V azques de Parga and A lvaradd<sup>4</sup> found values of the order 5-10 %. An earlier experiment using a Nitip, thus injecting spin-polarized electrons, and a Nipolycrystal sample also showed a large MCD upon reversal of the magnetization of the tip.<sup>10</sup>

Expressing the degree of polarization of the emitted light in terms of Stoke's parameters we have

+

$$= \frac{S_3^+ S_3}{S_0};$$
(1)

The superscripts on  $S_3$  and indicate whether the magnetization is parallel (+) or antiparallel () to the surface projection k, of the photon wave vector. Following

the de nition given by Jackson<sup>11</sup> and concentrating on <sup>+</sup>, left-circular polarized light (positive helicity) has the polarization vector  $\hat{}_{+} = (\hat{p} \quad i\hat{s}) = \frac{1}{p^2}$ , whereas for rightcircular polarization  $\hat{}_{-} = (\hat{p} + i\hat{s}) = \frac{1}{2}$ , where, see Fig.1,  $\hat{s} = \hat{x}$  and  $\hat{p} = \hat{}_{-}$  are s- and p-polarization unit vectors. In term s of the electric eld  $E_{sp}^{T}$  at the detector caused by the source at the tip (T), the Stokes parameters are

$$S_{0} \qquad j_{+} \qquad \overline{\xi}_{p} f + j \qquad \overline{\xi}_{p} f = \xi_{p}^{T} f + \xi_{s}^{T} f;$$

and

$$S_{3}^{+} \qquad \dot{J}_{+} \qquad \tilde{\xi}_{\mathcal{P}}^{-} \dot{f} \qquad \dot{f} \qquad \tilde{\xi}_{\mathcal{P}}^{-} \dot{f} = 2 \operatorname{Im} \left[ \mathbb{E}_{S}^{T} \operatorname{E}_{p}^{-T} \right]:$$

Asa result,

+

$${}^{+} = 2 \operatorname{Im} \frac{\operatorname{E}_{s}^{\mathrm{T}} \operatorname{E}_{p}^{\mathrm{T}}}{\operatorname{E}_{p}^{\mathrm{T}} \operatorname{f} + \operatorname{E}_{s}^{\mathrm{T}} \operatorname{f}} \qquad 2 \operatorname{Im} \frac{\operatorname{E}_{s}^{\mathrm{T}}}{\operatorname{E}_{p}^{\mathrm{T}}}; \quad (2)$$

where the last approximation follow specause  $\Xi_s^T$  jis normally much smaller than  $\Xi_p^T$  j for the particular set-up we are considering. Hence, the experimentally measured quantity is

$$2 \text{ Im} \quad \frac{E_s^T (\text{detector})}{E_p^T (\text{detector})} \qquad (M ! M): (3)$$

The basic physics behind these equations is that tunneling electrons undergoing inelastic events via spontaneous em ission produce a radiating eld in the vicinity of the tip. This leads primarily to em ission of p-polarized light, but when rejected in the surface of the magnetic sample it also gives rise to a small eld component in a direction parallel to the surface due to the K erre ect. We have thus expressed the measured M CD in terms of the eld amplitudes at the detector. To facilitate the ensuing calculations, we will next relate these tip-induced elds in the detector region to complementary elds generated by sources at the detector.

#### B.Reciprocity theorem

In this subsection we use the reciprocity theorem to reform ulate Eq. (3). The electrons tunneling inelastically between tip and sample can emit photons and are a source of electrom agnetic radiation. This radiation couples to tip and sample and is nally detected far from the tip. We have previously found<sup>12</sup> that it is convenient to use the reciprocity theorem of classical electrodynam ics<sup>13</sup> in such a situation because it allows the radiated eld to be approximately determined by a nonretarded calculation if the wavelength of the emitted light is large compared to the relevant tip extension. This theorem essentially states that the result of a measurement is unchanged if the source and eld points are interchanged. Here, the reciprocity theorem can be written as

$$\begin{array}{ccc} X & Z \\ & & & & \\ & & & \\ & & & & \\ & & & \\ & & & \\ & & & \\ & & & \\ & & & \\$$

where j denotes the components x, y, and z. The current  $J^{T(D)}$  at the tip (detector) is the source for the electromagnetic eld  $E^{T(D)}$ .

Equation (4) is valid form edia with tim e-reversal symmetry. However, a magnetic material does not full l this condition and one has to use a modi ed reciprocity theorem <sup>13</sup> whereby Eq. (4) can still be used provided the true medium is replaced by its complementary medium (one with reversed magnetic eld). If the dielectric tensor of the real medium is  $_{ij}$ , then the complementary medium has a dielectric tensor  $_{ij}^c$  which is the transpose of  $_{ij}$ ;  $_{ij}^c = _{ji}$ . The dielectric matrix has the form

where the notation  $_1(!)$  iQ  $_s(!)$  is sometimes used with Q being the so called magneto-optical constant and  $_s(!)$  is the substrate dielectric function. The angles

and specify the direction of the applied m agnetic eld with respect to the surface norm al and the plane of incidence. We see that the complementary medium corresponds to changing the sign of the o -diagonal components.

To a high degree of accuracy, the current between the tip and sample is spatially well-localized and perpendicular to the substrate. Thus we write

$$J_{j}^{T}(x) = 2J_{o}(jz)$$
 (6)

where  $\hat{z}$  is norm alto the surface, pointing inwards. The relative independence of  $E_z^D$  on position in the surface-tip region has been veried by numerical calculation<sup>14</sup> and is also a key feature of the models used in this paper. We can take out an average value of  $E^D$  in the region between tip and sample and write the right hand side of Eq. (4) as

$$E_{z}^{D} \quad dV J_{o}(;z) \quad jE_{z}^{D}:$$
(7)

 $E_z^D$  is the perpendicular component of  $E^D$ , with respect to the surface plane, i.e. in the z-direction. The electronic current from the STM ow sprim arily in the normal direction with respect to the surface, thus only a perpendicular component of a \detector-generated" eld can couple to that tunneling current.

On the left hand side of Eq. (4), we insert a current source with two components,

$$J^{D}(\mathbf{x}) = \mathbf{\hat{n}} \mathbf{j}_{n} (\mathbf{x} \mathbf{x});$$
(8)

where  $x_D$  is the detector position and  $\hat{n}$  corresponds to either the direction  $\hat{s}$  or  $\hat{p}$ . Notice that these currents

generate two di erent  $E_z^D$ , which we write as  $E_z^n$  in what follows (n= s or p). Eqs. (4), (7) and (8) yield

$$E_{n}^{T} (detector) j_{n} = j_{o} E_{z}^{n} :$$
(9)

C om bining Eq. (9) with Eq. (3) and also including the complementary-medium sign change we obtain

$$L^{+} 2 \operatorname{Im} \frac{\operatorname{E}_{z}^{s} = j_{s}}{\operatorname{E}_{z}^{p} = j_{p}} = 2 \operatorname{Im} \frac{\operatorname{E}_{z}^{s} = \operatorname{E}_{s}^{\operatorname{in} c}}{\operatorname{E}_{z}^{p} = \operatorname{E}_{p}^{\operatorname{in} c}}$$
(10)

and is <sup>+</sup> (M ! M). In the last line we have replaced  $j_{s,p}$  by the corresponding incoming eld strengths  $E_{s,p}^{in\,c}$  since s-polarization and p-polarization represent two orthogonal polarization states. Thus the reciprocity theorem makes it possible to express the tip-generated eld at the detector position ( $E_n^{\rm T}$  (detector)) as the elds in the tip region generated by incoming s- and p-polarized waves.

#### C.Determ ination of elds at STM tip

In this section we model the STM tip in such a way as to include the main physical e ects and to allow the development of a formalism for determining the elds at the tip. The system of tip and sample is a dicult one to treat for several reasons. Even if the tip was perfect, in the sense of having a well-characterized geometrical shape, the resulting electrom agnetic eld problem has relatively low symmetry. Consequently, we model the tip as a polarizable sphere of radius R, with a scalar polarizability  $_{0}(!)$ , situated a distance d = R + D from a surface. Then we replace the sphere with a dipole at d. In this way we include the relevant physics, such as a relatively constant eld in the region between tip and sam ple, while making the problem tractable. Since the circular polarization is a ratio between two quantities, we hope that a simpler model can capture the main features of the emitted light. A dipole model was also used to study the polar Kerre ect by Kosobukin<sup>15</sup> in the context of near eld optics. In section III we improve upon this by using the full sphere in the calculations. W e consider the non-magnetic situation in this section and introduce the m agnetic substrate in Sec. IID.

Consider a sphere centered at d= (0,0,-d) where -d is the position of the sphere outside a m etal surface whose optical re ection can be described in terms of its Fresnel re ection coe cients s and p for spolarized and p-polarized light, respectively. The tip (sphere) above the surface is replaced by a point polarizable dipole with polarizability  $_{0}(!)$ . The total electrom agnetic eld at the dipole position E (d,!) can be divided into two parts E <sup>ext</sup> and E<sup>t</sup>: E <sup>ext</sup> is the solution to M axwell equations with an incident electrom agnetic eld and no tip present while E<sup>t</sup> is a solution when we have no incom ing electrom agnetic eld but the induced eld at the tip plays the role of a source term. A ssum e the point dipole has an induced dipole m om ent  $P = (P_k, P_2)$ . The solution to the E<sup>t</sup> problem can be simplied if we decompose the induced eld at the tip in Fourier components parallel to the surface (k) and note that they play the role of incoming electromagnetic elds analogous to the situation in the E<sup>ext</sup>-problem, (how ever, we have to sum over all possible parallel wave vector components to get the total eld). The (near) eld from a dipole can be Fourier decomposed according to

$$E(x;!) = \frac{d^2k}{(2)^2}E(k;z;!)e^{ik} x$$
(11)

where E (k,z,!) is the analogue to an "incom ing" electrom agnetic eld. In our case the low est order m agnetic com ponent is smaller than the electric eld by a factor ! d/c = 1. The total eld from the dipole and its im age<sup>16</sup> is expressed in components parallel and perpendicular to the surface as

$$E_{k}^{t}(k;z;!) = ip E_{k}^{\circ} e^{ipz} + (_{s} \hat{T} E_{k}^{\circ} p(1 \hat{T}) E_{k}^{\circ}) e^{ipz} ]$$

$$(12)$$

and

$$E_{?}^{t}(k;z;!) = ik e^{ipz} + e^{ipz})$$
 (13)

where  $_{\rm s}$  and  $_{\rm p}$  are the rejection coe cients for s- and p-polarized light scattered from the surface. In Eqs. (12) and (13) we have introduced

$$E_{k}^{o} = \frac{2}{p} e^{ipd} [kP_{?} + pP_{k} + \frac{k^{2}}{p} \hat{T} P_{k}]$$
(14)

and the transverse projection operator in the surface plane is  $\hat{T} = 1$   $\hat{k}\hat{k}$ , where  $\hat{k}$  is a unit vector along k. Furtherm ore  $p^2 + k^2 = q^2 = !^2 = c^2$  for the wave vector q = (k,p) of the incoming eld. In order to use the reciprocity theorem above we expose the surface and the tip to an incom ing electrom agnetic eld E  $^{\rm inc}$ . In the absence of the tip the total eld would be E  $^{\rm ext} = E^{\rm inc} + E^{\rm re}$ , where E  $^{\rm re}$  is the rected eld. Upon introducing the dipole, it will develop an induced polarization

$$P(d) = _{o}(!) \mathbb{E}^{ext}(d) + \mathbb{E}^{t}(d)]$$
 (15)

where d = (0,0,-d) is the position of the dipole and  $E^{t}(d)$  is the image eld of the polarized tip due to the presence of P.O ne can show that  $t^{16}$  (see also Appendix A):

$$E^{t}(d) = F_{k}P_{k} + F_{?}P_{?}\hat{2}$$
 (16)

for P in the surface plane ( $P_k$ ) or perpendicular to it ( $P_2$ ). We have de ned the feed-back, or in age functions,

$$F_{k} = \frac{1}{2} \int_{0}^{Z_{1}} dkk \frac{e^{2ipd}}{ip} \left[ q^{2}_{s} (k; !) p^{2}_{p} (k; !) \right]$$
(17)

and

$$F_{?} = \int_{0}^{Z_{1}} dk k^{3} \frac{e^{2ipd}}{ip} [p(k;!)]$$
(18)

after performing an angular integration in the surface plane. The non-retarded limit for  $F_k$  and  $F_2$  is obtained by letting  $c \ \! ! \ 1 \!$  with the result that p is replaced by ik.

Equation (15) is a self-consistency condition on the induced dipole moment representing the tip. Solving for P we obtain

$$P_{i} = \frac{_{\circ} (!)}{1 _{\circ} (!)F_{i}} E_{i}^{ext} (d); \qquad (19)$$

where i = k and ?. The denom inator in Eq. (19) can be included with the eld to form an elective eld acting on the unperturbed tip (dipole) or it can be included with the bare polarizability  $_{\circ}$  to form an elective polarizability. For special frequencies, the coupled system exhibits resonances when Re( $_{\circ}F_i$ )=1 and P<sub>i</sub> can be very large. An explicit demonstration of this is found<sup>17</sup> for a sphere outside a surface. Combining Eqs. (15) and (16) we obtain the total eld at the dipole position,

$$E^{\text{tot}}(d) = P(d) = {}_{\circ}$$
  
=  $E^{\text{ext}}(d) + E^{\text{t}}(d)$   
 $E^{\text{ext}}(d) + G_{k}E^{\text{ext}}_{k}(d) + G_{2}\hat{z}E^{\text{ext}}_{2}(d);$  (20)

where  $G_{k;?} \ge e^{ext}$  is the eld at the tip, due to the image of the tip produced by  $P_{k;?}$ . We have introduced an image factor  $G_i$  dened as

$$G_{k;?} = \frac{\circ (!) F_{k;?}}{1 \circ (!) F_{k;?}}$$
(21)

For a substrate characterized by a frequency dependent dielectric function,  $_{\rm S}$  (!), we nd in the non-retarded lim it:

$$F_{?} = 2F_{k} = \frac{1}{4d^{3}} \frac{s(!)}{s(!)+1}$$
 (22)

In Eq. (21),  $_{\rm o}$  contains inform ation about the dipole resonances and F<sub>k;?</sub> contains inform ation about the surface (sam ple) resonances ( $_{\rm S}$  + 1=0 corresponds to surface plasm ons). From Eq. (21) we see how the tip and sam – ple couple to yield new eigenm odes at the poles of G<sub>k;?</sub>, and also a possible eld enhancement. In this respect our model contains all the features of more rened calculations for the STM con guration.<sup>14</sup> For the dipole (tip), we use the polarizability for a sphere of radius R and dielectric function  $_{\rm T}$  (!):

$$_{\circ}(!) = R^{3} \frac{T}{T}(!) \frac{1}{2}$$
 (23)

In this way one can also include a more accurate dielectric response of the tip, e.g. using measured values for  $_{\rm T}$ . The factor 2 in the denom inator is actually (-1+ 1/n)

where n is the so called depolarization factor. Thus we could also m in ic di erent tip shapes by choosing di erent values of n.

In the following discussion we retain Eq. (20) as a generic form for the resulting eld at the tip position when an incoming eld is incident on the tip and the sample. Notice also that the only boundary condition m atching is done in the absence of the tip. A fler this the self-consistency condition for the induced dipole moment [Eq. (15)] adjusts the total eld strength appropriately.

## D.Local eld near tip with m agnetic substrate

In section IIB we related the elds at the detector to the elds of the inverse problem where light is scattered from the tip. In the previous section we showed how the incoming eld is a ected by the presence of a tip outside a non-magnetic solid. Furtherm ore, we expressed the elds in term s of the total eld outside the substrate in the absence of the tip:  $E^{ext}(d)$  in Eq. (20). Now we will calculate  $E^{ext}(d)$ , and also consider the changes in the rejected dipole eld, in the presence of a magnetic sample. We rst address the eld felt by a tunneling electron that undergoes an inelastic event leading to the light em ission.

In the previous section we calculated the induced polarization at the tip in a self-consistent manner and obtained the eld at the tip position itself. A tunneling electron will not only fiel the incoming eld and the reected eld of the incoming light, but the tip-induced image eld as well as the direct dipole eld from the tip. In the region between the actual tip and substrate these elds vary only slightly since the dipole is far away from the surface, R >> D. We can write the eld acting on a tunneling electron as (i=k;?):

$$E_{i} = F_{o}P_{i} = F_{o} \circ (1 + G_{i}) (1 + i)E_{i}^{inc}$$
(24)

where all elds represent average values in between tip and sample.  $F_{\circ}$  is a the dipole factor which gives the eld strength for a given polarizability P. Notice that if we have no surface present  $E = F_{o;direct} \ _{o}E^{inc}$ , where  $F_{o;direct}$  is the direct part of  $F_{\circ}$ . We see that (1+G) plays the role of a eld enhancing factor for the incom – ing and scattered electrom agnetic elds from the surface  $(1 + )E^{inc}$ .  $_{\circ}$  is a property of the tip, G depends on both the sample and the tip, and ~ is a property of the sample.

To determ ine P we rst have to calculate the re ected eld from a magnetic surface and such a re ection involves the magneto-optic K err e ect. For general angles between applied magnetic eld, surface plane and plane of incidence there is an excellent treatm ent by Zak et al.<sup>18</sup> which is very useful when dealing with light re ection from a magnetic solid. For a general magnetic con guration the proper form of the dielectric matrix was given in Eq. (5). The o -diagonal elements of this tensor carry the inform ation about the K err e ect. The origin of the non-diagonal components is a coupling between the spin of the electrons in the solid and their orbitalm om entum due to the atom ic potentials (spin-orbit coupling). The rst theoretical calculations of this e ect were carried out by Hulm e<sup>19</sup> and Argyres.<sup>20</sup> Equation (5) assumes that the dielectric tensor is diagonal when  $_1(!) = 0$  (this approximation can be relaxed but it does not in uence our nal conclusions).

For the applied magnetic eld in the surface plane we can use Eq. (5) for the general dielectric tensor with

= =2 and one angle () su ces to specify the direction of M with respect to the plane of incidence. The dielectric matrix in Eq. (5) then simpli es to

We use this result in the Zak matrix multiplication method, together with an expansion to rst order in  $_1(!)$ , since the o -diagonal elements are small com – pared to  $_{\rm S}(!)$  (j  $_1(!) = _{\rm S}(!)$  j 1). However, these matrix elements provide a coupling between spolarization and p-polarization leading to a non-zero Kerr rotation. For s-polarized incident light (along x-direction),  $E_{\rm s}^{\rm inc}$ , our analysis gives the rejection coe cient for s-polarized light to lowest order in  $_1(!)$ , as

$$s = \frac{p - p_{s}}{p + p_{s}} + O(\frac{2}{1})$$
 (26)

which is the standard Fresnel result.<sup>11</sup>  $p = q^2 - k^2$  and for q > k, k = qsin with being the angle of incidence. For k >> q, p ! ik.  $p_s = q^2 - q^2 - (l) - k^2$ , with s (l) de ned above. Finally q = l/c, where c is the light velocity. Apart from the direct re-ection of s-polarized light there is a small but crucial conversion from s- to p-polarized light with a re-ection coe-cient

$$p_{s} = \frac{kpq}{p_{s} (p + p_{s}) (sp + p_{s})} \sin + O(\frac{2}{1}) \quad L \sin$$
(27)

It is proportional to  $_1(!)$  since it comes from the o-diagonal response. For large  $_{\rm S}$ ,  $_{\rm ps}$  /  $_1=\frac{2}{\rm S}$ . W ith Zak's eld conventions, Eq. (27) corresponds to a rejected eld amplitude,  $_{\rm ps} E_{\rm s}^{\rm inc} \sin$ , in the z-direction. It is clear from Eq. (27) that a general direction of the applied m agnetic eld in the surface plane corresponds to replacing  $_1(!)$  in the strictly longitudinal con guration ( = =2) by  $_1(!) \sin$  for the spolarized case. Changing the direction of M ( ! + ) changes the sign of  $_{\rm ps}$  as it should.

Repeating the same analysis as above for p-polarized incoming light we nd, to low est order in the o -diagonal elements:

$$p = \frac{sp}{sp+p_{s}} + m \cos + O({2 \choose 1})$$
(28)

with

$$T = \frac{2_1 (!) pk}{(s (!) p + p_s)^2} :$$
 (29)

The corresponding relection coecient for p- to spolarized conversion is  $_{sp} = _{ps}$ . The rst term in Eq. (28) is the standard Fresnel relection coecient for a non-magnetic solid.<sup>11</sup> For later use we need the nonretarded lim it of equations (28) and (29), viz.:

$${}_{p}^{o} = \frac{s(!)}{s(!)+1} + {}_{T}^{o} \cos + O({}_{1}^{2}); \qquad (30)$$

where

$${}_{\rm T}^{\circ} = \frac{2i_{1}(!)}{(s_{1}(!) + 1)^{2}}$$
(31)

The sttem in Eq. (30) is the classical in age factor for a solid with dielectric function  $_{\rm S}$  (!).

M aking use of the form alism of Zak et al.  $^{18}$ , we me that for an invadiated m agnetic surface we can make the following replacements with respect to the non-magnetic situation:

$$s! s + sp s L sin$$
 (32)

and

$$_{p}! _{p} + _{ps} _{p} + _{L} \sin + _{T} \cos :$$
 (33)

 $_{\rm L}$  is de ned in Eq. (27) and  $_{\rm T}$  is de ned in Eq. (29).

The change in rejection factors for a magnetic surface compared to the non-magnetic situation will also a ect the rejected eld from the tip. We are interested in the near-eld and therefore take the non-retarded lim it of  $_{\rm L}$ ;  $_{\rm L}^{\circ}$ :

$${}_{\rm L}^{\circ} = \frac{q_{1}(!)}{2k(s_{1}(!)+1)}$$
(34)

to bw est order. Notice that  $_{p}$  has a nite value [ $_{p}^{\circ}$  +  $_{T}^{\circ} \cos$ , cf. Eq. (30)] in this lim it and that  $_{s}$  vanishes as O ((q/k)<sup>2</sup>). In what follows, we neglect  $_{L}^{\circ}$  / q=k com – pared to  $_{T}^{\circ}$  since k !=c in the non-retarded lim it. Repeating the previous treatment for a magnetic material one nds [by letting  $_{s}$  and  $_{p}$  be transformed according to Eqs. (32) and (33)] that Eq. (16) is replaced by (see Appendix A):

$$E_{k}^{loc}(d) = F_{k}P_{k} \quad F_{T}P_{?}(\hat{z} \quad \hat{M})$$
(35)

and

$$E_{?}^{loc}(d) = F_{?}P_{?} + F_{T}P_{k} \quad 2(\hat{M})$$
 (36)

where  $\hat{M}$  is a unit vector in the surface plane in the direction of M and  $\hat{z}$  is norm alto the metal and directed towards  $\pm$ . The coupling factor due to the o -diagonal

response of the medium ,  $F_T$  , is given by (non-retarded lim it):

$$F_{T} = \frac{1}{2i}^{Z} dkk^{2} {}_{T}^{\circ} (k; !) e^{2kd} = \frac{1}{4d^{3}} \frac{1}{(s(!) + 1)^{2}} (37)$$

using  $^{\circ}_{T}$  from Eq. (31) in the last line. The physics behind the structure of the above equations is the follow ing. A perpendicular dipole [Eq. (35)] provides an electromagnetic eld which is rejected in the surface and gives an induced electric eld and dipole component parallel to the surface (due to K err response, through  $F_T$ ) and perpendicular to the magnetization M. A parallel dipole likew ise is rejected and provides an induced perpendicular to  $F_T$ . If both M and  $P_k$  are parallel there is how ever no such contribution.

## E. Theoretical results

We have now developed all the necessary ingredients for calculating the circular polarization from Eq. (10). First consider the case of incident s-polarized light at an angle . A eld  $E_s^{inc}$ \$ (along the x-direction, \$ = \$) sets up a parallel polarization of the tip

$$P_{k} = {}_{\circ} [(1 + {}_{s})E_{s}^{inc} \hat{x} + F_{k}P_{k} - F_{T}P_{?} (\hat{z} - \hat{M})] (38)$$

Eq. (15) and Eq. (35) have been used to derive Eq. (38). There is also a perpendicular polarization

$$P_{?} = {}_{o} [ \sin {}_{ps} {}^{(M)} E_{s}^{inc} + F_{?} P_{?} + F_{T} P_{k} \hat{z} (\hat{M})];$$
(39)

In the rst term we have indicated that the conversion coe cient ps is now, due to the exact form of the reciprocity theorem, to be evaluated in a situation which is the same as the one considered above if we change the sign of M. The Kerr coupling between the induced dipole m om ents of the tip is included through the coupling function  $F_T$ . In Eq. (39) the rst term is the z-component Kerr eld set up by the incom ing s-polarized light. The second term is the image from the tip-induced polarization perpendicular to the surface. Finally the third term is the image from the parallel induced dipole set up by the incoming s-polarized wave Eq. (38)] which is converted to a perpendicular component by the non-diagonal response of the substrate. The latter is described through  $F_T$  which is given above. N eglecting  $F_T$  in equation (38), substituting the resulting expression in equation (38) for  $P_k$  into equation (39) and using equations (15), (20) and (21) gives the eld experienced by an electron between tip and sample to lowest order in  $F_T$  [c.f. Eq. (24)]:

$$E_{z}^{s} = (1 + G_{?}) (_{o}F_{o})$$
$$[_{L} \sin (1 + _{s})G_{k}K (!)]E_{s}^{inc} \sin (40)$$

due to the incoming eld  $E_s^{inc}$ . We have used  $\hat{x} \hat{z}(\hat{M}) = sin$  and dened:

K (!) 
$$F_T = F_k = \frac{2_1(!)}{\binom{2}{s}(!)}$$
 (41)

Note that the right hand side of equation (40) is proportional to sin , the orientation of the magnetization in the surface plane; longitudinal polarization providing for the maximum eld strength.

 $E_{\tau}^{s}$  in equation (40) is the major part of the average eld in the z direction in the narrow region between tip and sample, created by the incoming s-polarized eld of m agnitude  $E_s^{inc}$ . The rst factor in Eq. (40) is understood as follows; an incoming s-polarized eld of magnitude E sin c undergoes a K err rotation and a eld proportional to L is created in the z direction. The tip acquires a z-component of polarization and radiates. This radiation is also re ected back to the tip by the surface, thus the tip sees its own image giving a contribution,  $G_{2}$  . The total eld at the tip is the original eld plus the im age eld. Thus, G<sub>?</sub> is an image (enhancement) factor due to the polarization of the tip in the 2 direction. The quantity G? depends on the dielectric properties of the tip, the metal, the distance between them, and on the geometry of the tip.

The second term in equation (40) is explained as follows;  $(1 + {}_{s})E_{s}^{inc}$  is the eld at the tip due to light that falls directly on the tip plus light that is rejected from the metal surface. The tip is then polarized in a direction parallel to the surface and it radiates. This s-polarized radiation is rejected in the surface and undergoes a K err rotation so that it develops a z-component. The term  $G_{k}K$  is the analogue of  $_{L}$  in the rst term . Once a eld is created in the z direction it is enhanced by the factor  $(1 + G_{2})$  in front.

Perform ing the above calculation for an incoming ppolarized wave with amplitude  $E_p^{inc}$  and working only to zeroth order in the o -diagonal dielectric matrix (since both terms in Eq. (40) above for s-polarized light are already of rst order in  $_1$  (!)) we nd:

$$E_{z}^{p} = (1 + G_{?}) (_{o}F_{o}) (1 + _{p}) \sin E_{p}^{inc}$$
 (42)

where sin  $E_p^{inc}$  is the eld that falls directly on the tip and  $_p \sin E_p^{inc}$  is the eld at the tip that is rejected from the surface. The total eld is enhanced by the same factor (1 + G<sub>2</sub>) as discussed above.

W ith the use of Eqs. (3), (10), (40), (41) and (42) this leads to the follow ing expression for the m agnetic circular dichroism, to low est order in  $_1$  (!):

+ = 4 sin Im 
$$\frac{L}{1+p}$$
 + G<sub>k</sub>  $\frac{1+s}{1+p}$   $\frac{K(!)}{sin}$ ;  
(43)

Note that the light enhancement factor G<sub>2</sub> from the perpendicular eld component drops completely out of the problem as does the dipolar factor  $F_0$  so the ratio does not depend on where in the junction the light emission takes place. In section III we will make a more realistic

estim ate of Eq. (43) for the m agnitude of the m agnetic circular dichroism. However, let us already here say that the fact that  $G_2$  drops out of the dipole-m odel calculation gives one hint to why this m odel, as we will see, yields results for the m agnetic circular dichroism that are of the right order of m agnitude although the eld enhancement (described by  $G_2$ ) in the dipolar m odel m ay be very di erent from that calculated in the improved m odel.

### III. IM PROVED THEORETICAL MODEL

Here we outline a calculation of the tip-induced MCD signal within a model geometry where the STM tip is represented by a sphere characterized by a bulk dielectric function  $_{\rm T}$  (!). This allows for a much better description of the tip polarization. Most of the calculational details are deferred to Appendix B.

W e set out to determ ine  $E_z^s$  in Eq. (10), and this is achieved via the following four steps. (i) The incoming s-polarized wave is relected by the sample surface. This yields a total eld E ext parallel to the surface. (ii) That eld in turn drives the model tip so that it sends out a eld that is re ected back and forth between the tip and sample. In this step, we need to extract the part of the eld that the tip sends onto the sam ple. (iii) N ext, due to the o -diagonal elements of the sam ple dielectric tensor, part of the electric eld parallel to, and incident on the sam ple is converted to a eld perpendicular to the surface as follows from Eq. (30). It is only at this stage that the m agnetic properties of the sample enters the calculation. (iv) In the last step, we calculate the degree to which the converted electric eld is enhanced inside the tip-sam ple cavity.

Step (i): W ith an s-polarized wave incident from the right (positive y) with electric eld  $E_s^{inc}$ , the Fresnel formulae yields a total eld just outside the sample surface given by

$$E^{ext} = E_{s}^{inc} (1 + s) = R E_{s}^{inc} \frac{2p}{p + p_{s}}$$
: (44)

Thus before introducing the model tip into the problem, we have an electric eld outside the sample that can be described (in the non-retarded lim it) by the scalar potential

$$ext = xE^{ext}$$
; (45)

where  $E^{ext} = E_{s}^{inc} [2p=(p + p_{s})]$ .

Step (ii): O noe the model tip is introduced into the problem  $^{\text{ext}}$  alone is no longer a solution of Laplace's equation in the region above the sam ple, instead another contribution  $_{\text{ind}}$  has to be added. U sing the appropriate boundary conditions for the E and D elds at the sam ple and tip surfaces  $_{\text{ind}}$  can be determ ined. In the following, we only want to keep the part of  $_{\text{ind}}$  that the

tip sends onto the sample. As we will see in Appendix B, this separation can be done by a simple inspection of the solution.

Step (iii): We proceed to nd the eld that is relected from the sample surface due to the second term in Eq. (30); this is the converted eld  $E^{\text{conv}}$ . Equation (30) de nes a surface response function  $(k;!) = {}_{p}^{0}$ , which in term s of incident and relected electrostatic potentials is de ned as the ratio  $[{}^{\text{re}}(k;!) = {}^{\text{inc}}(k;!)]$ . A further analysis shows that within a non-retarded treatment there is a local relation between  $\hat{x} = {}^{\text{pc}}_{nd}$  and  $\hat{z} = {}^{\text{pnv}}_{nd}$ ,

$$E_{z}^{conv}() = \frac{2_{1}(!)}{(_{S}(!) + 1)^{2}} \quad \& \quad \stackrel{\text{inc}}{\underset{\text{Ind}}{\text{inc}}}() : \quad (46)$$

Step (iv): In this nalstep, we calculate the enhancement of the converted eld due to the presence of the model tip. The converted eld discussed above can be represented in terms of a scalar potential °. Again, with the tip present, ° alone does not solve Laplace's equation; it must be supplanted by another contribution  $_{ind}^{c}$ . The calculation determining  $_{ind}^{c}$  is completely analogous to the one carried out in Ref. 12, the only di erence being that ° is the driving \force" in the present case. Having found ° and  $_{ind}^{c}$ , we evaluate the corresponding electric eld on the symmetry axis. This is the tip-induced contribution to  $E_z^{s}$  appearing in Eq. (10).

## IV . NUMERICAL RESULTS AND DISCUSSION

W e now present num erical results for the dipole m odel of the tip based on the expression in Eq. (43), and for the sphere m odel of the tip discussed in Sec. III. W e use experim ental optical data for the dielectric functions of the tip and the sam ple. The o diagonal matrix elements of the sample dielectric function,  $_1(!)$ , are obtained from m agneto-optic K err e ect m easurem ents. The literature contains m any detailed calculations and m easurem ents of the Kerre ect (no tip present). The Kerre ect is an optics e ect caused by the spin-orbit interaction that was discovered in the last century. The spin-orbit interaction is small in Fe and Cobecause the orbitalm omentum in 3d-m etals is sm all. It is only in this century that a m icroscopic theory has emerged.<sup>19 $\{22\}$ </sup> The Kerr e ect has recently been calculated by a num ber of groups for a variety of elements and compounds (see, e.g. Gasche et al. and Delin et al.23;24). Sim ilarly, on the experim ental side there have been a num ber of measurem ents from those of K rinchik and A rtem 'ev<sup>25</sup>, whose results we use to obtain  $_1$  (! ), to the recent results of W eller et al.<sup>26</sup>

E quation (43), derived for the dipole model, consists of two terms; the rst corresponds to the direct K err rotation by the sample and the second to the K err rotation of the light produced by the radiating polarization of the STM tip as previously discussed. W e will refer to the two e ects as the substrate K err e ect and the tip K err e ect. In order to use the dipole model to make an estimate of the tip-induced K erre ect we calculate  $G_k$  from Eqs. (21), (22), and (23). The distance between the surface and the tip (i.e. from the surface to the sphere) is very small compared to the tip radius so that d = R in Eqs. (22) and (23) and  $G_k$  is determined by using experimental values for the dielectric functions of the tip and sample. W hen comparing our results in Eq. (43) with the experiments of V azques de P arga and A lwarado<sup>4</sup> and P ierce et al.<sup>7</sup>, we immediately recognize that in the longitudinal conguration that they use, \$ and  $\hat{M}$  are perpendicular to each other so that sin = 1.

C onsidering the improved (sphere) model, the quantities entering Eq. (10) were calculated as outlined in Sec. III and Appendix B. As for the model geometry we here used a tip-sample distance D = 5 A, and the tip radius R was set to 300 A.

The results of the calculations for the degree of circular polarization, + , are presented in Fig. 2. Figure 2 (a) displays the results obtained with a Co sample, while Fig. 2 (b) shows the results relevant for a Fe sample. In each panel, the results for the substrate K err contribution (one single curve) and the tip-induced contribution (four curves) to the degree of polarization are presented separately. The tip-induced degree of polarization has been calculated for Ag and W tips, respectively, using either the dipole m odel or the sphere m odel. The sphere m odel gives a larger degree of circular polarization than the dipole model, because it is a better description of the local electrom agnetic interaction between the tip and the sample. In our calculational schemes, the tip-induced contribution ultimately results from a Kerr rotation of the electrom agnetic elds incident from the tip onto the sample. The strength of the incident eld is determ ined by how strongly the tip is excited by the incom ing s wave as well as by waves re ected back and forth between the tip and sam ple. The sphere m odel allows for a m ore com plete treatm ent of the repeated re ections than the dipole m odel, and therefore gives larger values for  $\ ^{+}$ .The dipole approxim ation works fairly well because the circular polarization is given by the ratio of p and s electric elds.

The e ects of the tip-sample interaction is particularly pronounced for a silver tip. An isolated sphere has a dipole-plasm on resonance when the dielectric function  $_T$  (!) = 2. For silver, the dielectric function approaches this value near 3.5 eV. Then the model tip becom es highly polarizable and the feedback mechanism, the waves relected between the tip and the sample, described above becom es even more elective. In connection with this the electrom agnetic response functions that enter our calculations undergo large phase shifts so that

<sup>+</sup> changes sign one or several times.<sup>28</sup> The relatively smallm agnitude of the results for the MCD is due to the factor ( $_{\rm S}$  + 1)<sup>2</sup> in the denom inator in Eqs. (31) and (46). Since  $_{\rm S}$  for both Co and Fe is rather large this suppresses the MCD signal. From bulk arguments one could have assumed that the circular dichroism should

be proportional to  $_{1}=_{s}$ . However the presence of the surface changes the magnitude of both the eld going into the solid to be K err rotated and the resulting eld going out again; in both cases with a factor  $1=(_{s}+1)$ .

It is im mediately clear that within the model we have considered, there is no explanation for the large values for the degree of light polarization found by V azques de Parga and Alvarado.<sup>4</sup> The calculated results are an order ofm agnitude orm ore smaller than the experimental results found in R ef. 4. Even though we use a rather sim ple model for the geometry as compared with the complicated, and to a certain degree unknown geom etry of a realSTM tip, we cannot see how this could make up for the very large di erence between experim ental and theoretical results. Varying the geom etry param eters within reasonable lim its (within a non-retarded form ulation the results depend only on R/D) can change the calculated degree of polarization by a factor of 2 at most. This is also the case when using di erent sets of optical data for the dielectric functions entering. On the other hand, our calculated results are consistent with the experimental results found by Pierce et al.<sup>7</sup> on Fe sam ples. Our results are also small compared to those obtained in the calculations of M a jlis et al.,<sup>5</sup> som e of the reasons for this are given in a footnote.29

O ur results are not a ected by the assumption of a bulk sample compared to the very thin Co (100A) lm on A u<sup>4</sup>, provided it can still be described with bulk dielectric data. Calculations by M oog et al.<sup>30</sup> indicate that there are no fundam ental changes in actual numbers for lm s ranging in thickness between 100 Angstrom and 400, except a slight enhancem ent of the K err param eters.

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# APPENDIX A:

In this appendix we show how to evaluate the di erent angular integrations required in averaging the local dipole eld over a magnetic surface.

We rst have a look at the integrations for the nonmagnetic case. In this instance we have three types of integrals appearing  $d^2k(\hat{\Gamma} \quad \hat{F}_k)$ ,  $d^2k(k \quad \hat{F}_k)$  and  $R^2kE_k^{\circ}$ . They can be expressed in terms of the three integrals  $d^2k\hat{k}$ ,  $d^2k(\hat{k} \quad \hat{F}_k)$  and  $d^2k(\hat{k} \quad \hat{F}_k)$ . Perform ing the angular integration we nd that the rst integral is identically zero. Since the second integral is P<sub>k</sub> dotted with the rst integral it also vanishes. This leaves the third integral (where ' is the angular variable):

$$Z = \frac{d'}{2} \hat{k} (\hat{k} - R) = \frac{1}{2} P_k : \qquad (A1)$$

This result is obtained by expressing  $\hat{k}$  as  $\hat{x} \cos' + \hat{y} \sin'$ and  $\hat{k} = P_x \cos' + P_y \sin'$ .

In the magnetic case we have two extra angular factors in the integrand compared to the non-magnetic case; sin and cos . Expressed in terms of  $\hat{k}$  they are  $\hat{k}$   $\hat{M}$  and  $\hat{z}$   $\hat{M}(\hat{k})$ , where  $\hat{M}$  is a unit vector in the direction of the applied magnetic edd. Repeating the same steps as above we nd that all integrals can be expressed in terms of the following four integrals:  $d^2k(\hat{z} \quad \hat{M}(\hat{k}))$ ,  $d^2k\hat{k}(\hat{z} \quad \hat{M}(\hat{k}))$ ,  $d^2k[(\hat{k} \quad \mathbb{R})(\hat{z} \quad \hat{M}(\hat{k}))]$  and,  $d^2k[\hat{k}(\hat{k} \quad \mathbb{R})(\hat{z} \quad \hat{M}(\hat{k}))]$ . The rst and last integrals vanishes since they are odd in  $\hat{k}$ . The second integral becomes  $\frac{1}{2}(\hat{z} \quad \hat{M})$  using Eq. (A 1). For the third integral we obtain:

$$\frac{d'}{2} (\hat{k} - R) (\hat{z} - M(\hat{k})) = \frac{1}{2} P_k (\hat{z} - M(\hat{k}))$$
(A2)

again expressing the di erent vectors in  $\hat{x}$  and  $\hat{y}$  com ponents and using Eq. (A1). W ith the use of these results it is a straightforward manipulation to arrive at Eqs. (35) and (36).

#### APPENDIX B:

This Appendix explains the calculations outlined in Sec. III in more detail. To carry them out we use bispherical coordinates,<sup>31</sup> furtherm ore, to facilitate the connection with sim ilar, earlier calculations by  $us^{12}$  and others,<sup>32</sup> we also introduce another C artesian coordinate system  $(x^0; y^0; z^0)$  in which  $x^0$  and  $z^0$  are reversed com – pared with x and z, see Fig. 3. The bispherical coordinates (;;'^0) are de ned by

$$z^{0} = \frac{a \sinh}{\cosh \cos}; \quad x^{0} + iy^{0} = \frac{a \sin e^{i'^{0}}}{\cosh \cos}; \quad (B1)$$

Both the sample surface  $(z^0 = 0, = 0)$  and the sphere

$$= _0 = \ln (1 + (D + a) = R);$$

are constant surfaces. The length scale is set by the parameter

$$a = {p \over D^2 + 2RD}$$
:

Let us em bark on the calculations described in Sec. III. Step (i) is a straightforward application of the Fresnel formulae that yields an external potential  $ext = xE^{ext} = x^{0}E^{ext}$  [see Eq. (45)] describing the electric eld of an s polarized wave rejected of the sample surface. In the bispherical coordinates this potential can be written

$$e^{\text{ext}} = E^{\text{ext}} \frac{p}{8} a^{p} \frac{1}{\cosh \cos h} \cos \frac{x^{i}}{\cos h} e^{(n+1=2)j} p_{n}^{1} (\cos s) \cos'^{0}$$
(B2)

Proceeding to step (ii), we introduce the induced potential ind, and make the Ansatz

$$ind = \frac{p \cdot R}{8 \text{ a } E \exp^{p} \cdot \cos h} \cos \frac{X^{2}}{F_{n}()P_{n}^{1}(\cos)\cos'^{0}}; \quad (B3)$$

In the sample ( 0), the function  $F_n$  ( ) is given by

$$F_n() = (A_n + B_n)e^{(n+1-2)}$$
; (B4a)

in the tip  $( _0)$ 

$$F_n$$
 () =  $(A_n e^{(2n+1)} + B_n)e^{(n+1-2)}$ ; (B4b)

and nally, between the sample and tip  $(0 _{0})$ 

$$F_n$$
 ( ) =  $A_n e^{(n+1=2)} + B_n e^{-(n+1=2)}$  : (B4c)

Thus,  $F_n$ , ind, and therefore the tangential E eld is continuous across the tip and sample interfaces. From the form of Eq. (B4c) it is clear that the eld that the tip sends onto the sample is contained in the  $A_n$  term s; these elds decay exponentially as one goes away from the tip.

To determ ine the coe cients,  $A_n$  and  $B_n$  we must also dem and that the displacement eld perpendicular to the sample and tip surfaces is continuous across these interfaces. At the sample this means that

$$s \frac{\theta_{ind}}{\theta} \dot{j}_{=0} = \frac{\theta_{ind}}{\theta} \dot{j}_{=0+}$$
 (B5)

(here s is the sample dielectric function), which yields

$$B_n = {}_{S} A_n; \qquad (B 6)$$

where the sam ple surface response function

$$_{\rm S} = \frac{\rm s}{\rm s} \frac{\rm 1}{\rm s} + 1$$
 (B7)

Note that the contribution to D<sub>2</sub> coming from <sup>ext</sup> is already continuous since the external potential results from using the Fresnel form ulae. At the tip-vacuum interface  $( = _0)$ , both <sub>ind</sub> and <sup>ext</sup> must be considered in the boundary condition for D<sub>2</sub>. This yields an equation system involving the coe cients A<sub>n</sub>

$$U_{n}^{s}A_{n} + V_{n}^{s}A_{n-1} + W_{n}^{s}A_{n+1} = S_{n};$$
 (B8)

where

$$U_{n}^{s} = (2n + 1) \cosh_{0} e^{(n+1-2)} S_{T} e^{(n+1-2)};$$
  
+ sinh  $_{0}$  T  $e^{(n+1-2)} S_{S} e^{(n+1-2)}$  (B9a)

$$V_n^s = (n \quad 1) e^{(n \quad 1=2)_0} \quad s \quad T e^{(n \quad 1=2)_0} ; (B \ 9b)$$

$$W_n^s = (n+2) e^{(n+3=2)} S_T e^{(n+3=2)}$$
; (B9c)

and

$$S_{n} = \prod_{T}^{n} e^{(n+1=2)} \sup_{(n+1=2)} (\sinh_{0} (2n+1) \cosh_{0}) + (n-1)e^{(n-1=2)} (n+2)e^{(n+3=2)} (n+3=2) e^{(n+3=2)} (B 9d)$$

One arrives at these equations through a procedure that is completely analogous to the one used in earlier calculations.<sup>12;32</sup> Solving Eq. (B8) for the  $A_n$  coe cients, we can determ ine the tip-induced potential incident on the sample,

Next, we have to consider the electric eld conversion at the sample surface due to the o -diagonal components of the dielectric tensor in Eq. (25). In the primed coordinate system, it takes the form

Let us use this to calculate the modi ed sample surface response function. If a potential

$${}^{\text{inc}} = e^{ik} e^{kz^0} e^{-i!t}$$
(B12)

acts on the sample, its response yields another contribution to the potential above the surface

$$r^{e} = {}_{s} (k;!) e^{ik} e^{kz^{0}} e^{i!t};$$
 (B13)

where  $_{\rm S}$  (k;!) is the surface response function. C om bining these two contribution to the potential with a solution to Laplace's equation inside the sample

$$tr = T(k;!)e^{ik} e^{kz^{0}}e^{i!t};$$
 (B14)

and applying the usual boundary conditions, we obtain using Eq. (B11) that

$$S(!) = \frac{S}{S+1} + \frac{2i_{1} \sin(1 + \frac{7}{k})}{(S+1)^{2}}; \quad (B15)$$

where  ${}^{\prime}{}^{0}_{k}$  is the angle between k and  $\hat{x^{0}}$ .

The second term in Eq. (B15) is our main concern; it governs the electric eld conversion at the surface of the magnetic sample. In view of Eq. (B15) we write the potential corresponding to the converted eld as

$$conv(k) = \frac{2i_1(!)}{(s+1)^2} \sin(s+t'_k^0) \lim_{k \to \infty} k(k): \quad (B16)$$

Since we do not know the Fourier transform  $\inf_{ind}^{inc}(\mathbf{k})$  we cannot im mediately use this relation. However, specializing to the longitudinal conguration ( = =2) and using the fact that on the sample surface,  $\inf_{ind}^{inc} = f()\cos'^{0}($  is the distance to the symmetry axis), one can show that with M = M  $\hat{y}^{0}$  there is a local relation between  $\hat{x}^{0}$   $\inf_{md}^{nc}$  and  $\hat{z}^{0}$   $E^{onv}$ ,

$$E_{z^{0}}^{conv}() = \frac{2_{1}(!)}{(_{S} + 1)^{2}} \hat{x^{0}} \stackrel{\text{inc}}{E_{nd}}() : \qquad (B17)$$

The calculation leading to Eq. (B17) also shows that both these elds can be written on the form  $f_0() + f_2()\cos 2'^0$ , where  $f_0$  and  $f_2$  are functions of . The second term obviously cannot induce an electric eld possessing a  $z^0$  component on the symmetry axis of the tip-sample system, so we neglect it from now on. The cylindrically symmetric part of the eld E <sup>conv</sup>() can be derived from a potential written as

$$c = \frac{p}{2} a^{p} \frac{X^{d}}{\cosh \cos x} T_{n} e^{(n+\frac{1}{2})} P_{n} (\cos );$$
(B18)

The coe cients T<sub>n</sub> in Eq. (B18) can be calculated with the aid of Eq. (B17). To this end we extract the cylindrically symmetric part of  $\hat{x}^0$   $\frac{1}{Md}$  by taking the average of its values on the  $x^0$  and  $y^0$  axis, respectively, and rew rite these expressions as sum s of Legendre polynom ials only. At the expense of introducing a more complicated prefactor this yields

$$\hat{x}^{0} \qquad \underbrace{\lim_{m \to \infty} (x^{0})}_{m \to m} = \frac{p}{8} \underbrace{E}_{ext} \frac{p}{1 \cos x} \frac{1}{1 + \cos x} \int_{0}^{x^{0}} C_{n}^{x^{0}}(y^{0}) P_{n} (\cos x);$$
(B19)

where the superscript  $x^0(y^0)$  indicates whether the eld is evaluated on the  $x^0$  or  $y^0$  axis. The coe cients C  $_n^{x^0}$ and  $C_n^{y^0}$  are given by rather lengthy expressions involving the A<sub>n</sub> coe cients. It is also possible to rew rite E  $_{z^0}^c$ resulting from the  $z^0$  gradient of Eq. (B18) as a sum of Legendre polynom ials preceded by the same prefactor as in Eq. (B19). From Eq. (B17) we then obtain the follow – ing equation system determ ining the  $T_n$ 's

$$v_{n}T_{n} _{2} + u_{n}T_{n} + w_{n}T_{n+2} = \frac{1}{(s+1)^{2}} E^{\text{ext}} (C_{n}^{x^{0}} + C_{n}^{y^{0}});$$
(B20)

$$v_{n} = \frac{1}{4} \frac{(n-1)n}{2n-1};$$

$$u_{n} = \frac{1}{4} 2n + 1 \frac{(n+1)^{2}}{2n+3} \frac{n^{2}}{2n-1}; \text{ and}$$

$$w_{n} = \frac{1}{4} \frac{(n+1)(n+2)}{2n+3}: \quad (B21)$$

The nalstep amounts to solving for the enhancement of the  $z^0$  component of the electric eld between the tip and sample due to the presence of the tip. In fact, to obtain the nalresult for the degree of circular polarization, this calculation has to be done with two dierent driving forces. On one hand, using <sup>c</sup> as a driving force we obtain  $E_z^s$  to be used in Eq. (10), if instead, as in Ref. 12, the potential corresponding to a relected p wave is used to drive the tip-sample system, we obtain  $E_z^p$  to be used in Eq. (10). The two calculations can be done in parallel. We make an Ansatz for the potentials induced due to the presence of the tip in the two cases

$$r_{\text{ind}}^{c(p)} = \frac{p}{2} \frac{p}{a} \frac{p}{\cosh} \frac{X}{\cos} F_n^{c(p)} ()P_n (\cos);$$
(B22)

where the superscripts c and p, respectively, indicate that it is either the converted eld or an incom ing p wave that plays the role of driving force. In the sample (0),

$$F_n^{c(p)}() = A_n^{c(p)} e^{(n+1-2)(} + B_n^{c(p)} e^{(n+1-2)(} + o);$$
(B 23a)

in vacuum (0  $_0$ )

$$F_{n}^{c(p)}() = A_{n}^{c(p)}e^{(n+1=2)(0)} + B_{n}^{c(p)}e^{(n+1=2)(0)};$$
(B 23b)

and in the tip  $( _{0})$ ,

$$F_n^{c(p)}() = A_n^{c(p)} + B_n^{c(p)} e^{(n+1-2)(0)}$$
: (B23c)

The external potential in the case of the converted eld is given by Eq. (B 18)

$$c = \frac{p}{2} a \frac{p}{\cosh} \frac{X^{\frac{1}{2}}}{\cos h} T_{n} e^{(n+\frac{1}{2})} P_{n} (\cos);$$

whereas in the case of an incom ing p wave it is

$$\sum_{p=1}^{p=1} = \sin \frac{2 s p}{s p + p_{t}} E_{p}^{inc} \sum_{p=1}^{p} \frac{p}{2a} \cos h \cos \frac{x^{t}}{\cos h} \cos \frac{x^{t}}{(2n + 1)e^{(n + 1 = 2)}} P_{n} (\cos ); \quad (B24)$$

where the rst factor /  $E_p^{inc}$  is the resulting  $z^0 \mod po$ nent of the E eld just outside the sample surface as obtained from the Fresnel form ulae.

where

Proceeding along the same lines as when deriving Eq. (B 8), we rst obtain

$$B_n^{c(p)} = A_n^{c(p)} e^{(2n+1)_0} s$$
 (B25)

and then the equation system s

$$U_n A_n^c + V_n A_{n-1}^c + W_n A_{n+1}^c = S_n^c$$
 (B26)

and

$$U_{n}A_{n}^{p} + V_{n}A_{n-1}^{p} + W_{n}A_{n+1}^{p} = S_{n}^{p}$$
(B27)

determ ining the enhancem ent due to the presence of the tip of the converted eld and the p polarized wave, respectively. The coe cients on the left hand side are the same in both cases,

$$U_{n} = (2n + 1) \cosh_{0} 1 \qquad s \ T e^{(2n+1)_{0}}$$
  
$$T \sinh_{0} 1 \qquad s e^{(2n+1)_{0}}; \qquad (B 28a)$$

$$V_n = n \ 1 \ _{S \ T} e^{(2n \ 1)_0}$$
; (B28b)

$$W_n = (n + 1) 1_{S T} e^{(2n + 3)}$$
 (B28c)

The right hand side in Eq. (B26) is

$$S_{n}^{c} = {}_{T} e^{(n+1=2)} {}_{0} f[\sinh {}_{0} (2n+1)\cosh {}_{0}]T_{n}$$
$$+ ne^{0}T_{n} {}_{1} + (n+1)e^{-0}T_{n+1} ; (B29)$$

while for the case of an incident p wave we obtain

$$S_{n}^{p} = \sin \frac{2 sp}{sp + p_{t}} E_{p}^{inc} T e^{(n + 1 = 2)}$$
  
f (2n + 1) [(2n + 1) cosh 0 sinh 0]  
(2n<sup>2</sup> n)e<sup>0</sup> (2n<sup>2</sup> + 5n + 3)e<sup>0</sup> : (B 30)

Once all the coe cients A  $_{n}^{c}$  and A  $_{n}^{p}$  have been determined using Eqs. (B25), (B26), and (B27), we can calculate the resulting electric elds on the symmetry axis as

$$E_{z^{0}}^{s} = \frac{\cosh \cos \theta}{a} \frac{\theta^{c}}{\theta} + \frac{\theta^{c}_{ind}}{\theta}; \quad (B31)$$

and

$$E_{z^{0}}^{p} = \frac{\cosh \cos}{a} \frac{e_{p}^{ext}}{e} + \frac{e_{ind}^{p}}{e} : \quad (B 32)$$

The degree of polarization of the em itted light is found from

$$^{+} = \frac{S_3}{S_0}$$
  $2 \text{ Im } \frac{E_s^{\text{out}}}{E_p^{\text{out}}}$ ; (B 33)

so that using the reciprocity theorem , keeping in m ind the sign change of  $_{\rm 1}$  discussed earlier

4 Im 
$$\frac{E_{z^0}^{s}}{E_{z^0}^{p}}$$
: (B 34)

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- <sup>29</sup> The dielectric tensor of M a jlis et al.<sup>5</sup> is unphysical. The o diagonal elements are constructed from the diagonal ones, an approach for which there is no theoretical justi cation, and the constructed tensor does not obey proper symmetry conditions for an absorbing medium. Furtherm ore the corresponding expression to our ps is not correct.
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FIG.1. The schematic experimental set-up in the experiments of V azques de Parga and A lvarado<sup>4</sup> and Pierce et al.<sup>7</sup> showing the relative orientation of the applied magnetic eld (M) in the plane of the Co(0001)/Fe(001) surface (x,y plane), tungsten tip orientation, and optical detection axis. W ith the help of the so called reciprocity theorem [Eq. (4)] one can relate the eld intensity at the detector due to a current at the tip (E<sup>T</sup> (detector)) to the \detector-generated" eld intensity between tip and sample (E<sup>D</sup>). The latter is easier to construct and hence makes it rather straightforward to nd the eld we are most interested in; the one in the tip region. S and  $\beta$  denote two orthogonal polarization directions at the detector.



FIG.2. Calculated results for the circular polarization for (a) a Co sample, and (b) a Fe sample. Each of the gures present results obtained from both the dipole model (dotted curves) and the improved (sphere) model (full curves), moreover, results corresponding to A g and W tips (as indicated next to the curves) as well as the substrate K err contribution are displayed in both panels. In the sphere-model calculation we used R = 300 A for the tip radius and D = 5 A for the tip-sample separation. The sphere model in general gives a larger tip-induced contribution to the degree of polarization, nevertheless the results obtained with the two di erent m ethods have m any qualitative features in common.



FIG.3. Schem atic illustration of the coordinate system used in the improved model calculation.